

**Search Notes****Application/Control No.**

10/618,365

**Examiner**

Syed Zaidi

**Applicant(s)/Patent under Reexamination**

NAKAMICHI ET AL.

**Art Unit**

2609

**SEARCHED**

Class	Subclass	Date	Examiner
370	392	2/14/2007	SZ
370	389	2/14/2007	SZ
370	351	2/14/2007	SZ
370	359	2/14/2007	SZ
710	316	2/14/2007	SZ
710	317	2/14/2007	SZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in databases: uspat,us-pgpub,epo,jpo, ibm_tdb (see search strategy)	2/14/2007	SZ
Nakamichi et al.	2/14/2007	SZ
370/392 370/389 370/351 370/259 370/379).ccls.	2/14/2007	SZ
(IEEE Xplore Database( <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a> )	2/14/2007	SZ
(710/316 710/317.ccls.	2/14/2007	SZ
Consulted with SPE Rafael Perez-Gutierrez and SPE Asst George Bugg	2/14/2007	SZ